

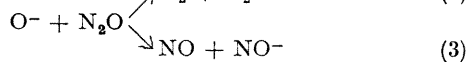
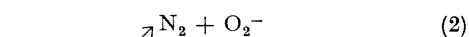
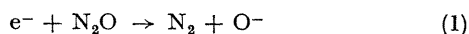
Ionic Processes in the Radiolysis of Nitrous Oxide

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Summary The addition of small amounts of sulphur hexafluoride to nitrous oxide before irradiation reduces the nitrogen yield by an amount which indicates that more than one nitrogen molecule is produced for each electron arising from the ionisation of the nitrous oxide.

RECENTLY,¹ the effect of small additions of SF₆ on the G-value for N₂-formation from gaseous N₂O was reported; G(N₂) was reduced from 10.1 in pure N₂O to 8.0 in the presence of 0.01–0.3% SF₆. This observation was used in reaching the conclusion that one electron produces one, or less than one, molecule of N₂, and hence that the mechanism



cannot apply since it implies that more than one N₂ molecule should be produced per electron.

We were not aware of the work of Takao, *et al.* when, during a study^{2,3} of the effects of N₂O and SF₆ on *cis-trans* isomerisation reactions, a few experiments were carried out to determine the effect of small amounts of SF₆ on G(N₂) from irradiated N₂O at temperatures from 30 to 200°. The results obtained, however, are sufficiently different from that cited to cast some doubt on the conclusion that one, or less than one, N₂ molecule is formed per electron.

The irradiations were carried out in a 1.9 l. silica vessel at a pressure of 80 cm. Hg (at 20°). The γ-ray dose rate was about 2 × 10¹⁹ ev l.⁻¹hr.⁻¹. At each temperature a set of irradiations of 3–20 hr. duration was used to construct yield–time curves for N₂ from which initial rates could be estimated. Gas chromatography was used for the analyses.

The initial rates, converted to G-values by assuming G(N₂) = 11.0 from pure N₂O at near-ambient temperatures,⁴ are shown in the Figure as a function of temperature and SF₆ content. At 30°, G(N₂) is reduced from 11.0 to 7.2, or 3.8 G units, by the addition of 1.0 vol. % SF₆. With increasing temperature G(N₂) from pure N₂O rises smoothly, in reasonably good agreement with the findings of Jones and Sworski⁵ (but not with those of Gorden and Ausloos⁶), while the residual G(N₂) in the presence of 1% SF₆ rises only very slowly. With 0.1% SF₆ the N₂ yield is slightly lower and invariant with temperature; it appears possible that an excess of SF₆ can contribute to N₂-formation in some way.

On the assumption that SF₆ acts only as an electron scavenger, the change in G(N₂) of 3.8 units at 30°, taken in conjunction with W(N₂O) = 33.0, gives G(e⁻) = 3.0 and indicates that about 1.3 N₂ molecules are produced for each electron arising from the ionisation of N₂O. This means that reactions (1)–(3) can in fact account for the ionic contribution to N₂-formation at that temperature. Since the curves in the Figure appear to be approaching limiting values at the lowest temperature, it may be valid to compare the present results with those of Robinson and Freeman,⁷ obtained at –88° with pure N₂O. On the basis of

their results a mechanism was suggested which included reactions (1)–(3) and yielded G(N₂) = 3.5 as the sum of (1) and (2). The agreement of this conclusion with the present work gives substance to the view that reactions (1) and (2), or equivalent reactions involving N₂O⁻, do occur during the radiolysis of N₂O.

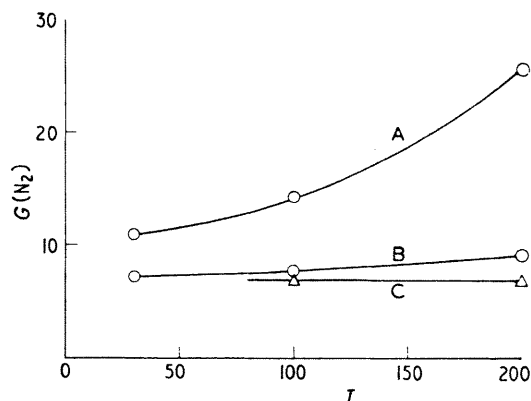
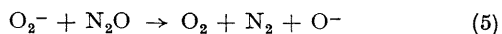
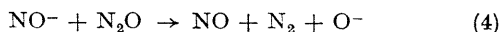


FIGURE. Variation of G(N₂) with temperature and the effect of added SF₆; A: Pure N₂O; B: N₂O + 1 vol. % SF₆; C: N₂O + 0.1 vol. % SF₆.

The relative constancy of G(N₂) with rising temperature in the presence of SF₆ is evidence that most of this N₂ is produced by reactions such as N₂O* → N₂ + O, which require no activation energy acquired by collisions with other molecules. On the other hand, the ionic processes inhibited by SF₆ obviously require some activation energy; these will be processes subsequent to reactions (1)–(3) or their equivalents, which we assume from the apparent attainment of a limiting value for G(N₂) at low temperatures require no activation energy. Gorden and Ausloos⁶ suggested the reactions



their measurements indicating that (4) is more probable. As they pointed out, these reactions regenerate O⁻ and thus can account for the temperature effects which they, by isotopic analyses, and we, by the use of SF₆, have observed.

The present results seem to agree well with the mechanistic implications of the work of Freeman⁷ and Ausloos,⁶ rather than with those of Takao.¹ It is possible that the total dose (7.2 × 10²⁰ ev g.⁻¹) given in the latter work was excessive; it has been shown^{4,8} that the N₂ yield is no longer linear with dose above 3–6 × 10²⁰ ev g.⁻¹. At higher doses G(N₂) from pure N₂O would tend to be low, whereas in the presence of SF₆ the accumulation of N₂, which is formed mainly from N₂O*, would probably still be linear with dose. The difference would thus be incorrectly low.

A very recent Note by Sears⁹ reports a reduction in G(N₂) of 3.2 ± 0.5 by the electron scavengers SF₆, NO₂,

and CCl_4 and casts doubt on the importance of reaction (2). However, from his tabulated results it would seem reasonable to take weighted averages of $G(\text{N}_2)$ for γ -irradiated pure N_2O in the gas phase at densities up to 0.10 g. cm.^{-3} and for all his results with N_2O at 800 torr containing varying amounts of SF_6 , NO_2 , and CCl_4 . This calculation

yields $\Delta G(\text{N}_2) = 10.6 - 7.1 = 3.5$ and thus provides support for the present contention that reaction (2), or its equivalent, is important in the radiolysis of N_2O .

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